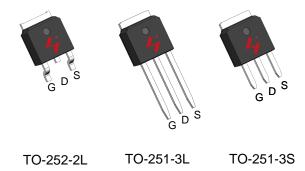


### N-Channel Enhancement Mode MOSFET

### **Features**

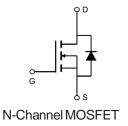
- 60V/55A,  $R_{DS(ON)}$ =10.5 m $\Omega$  (typ.) @  $V_{GS}$ =10V
- Avalanche Rated
- Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)

### Pin Description



## **Applications**

Power Management for Inverter Systems.



## Ordering and Marking Information



Package Code

D : TO-252-2L V : TO-251-3S

Date Code YYXXX WW U : TO-251-3L

Assembly Material G: Lead Free Device

Note: HUAYI lead -free products contain molding compounds/die attach materials and 100% matte tin plate Termination finish; which are fully compliant with RoHS. HUAYI lead -free products meet or exceed the lead-free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



# **Absolute Maximum Ratings**

Symbol	Parameter	Rating	Unit	
Common F	Ratings (T <sub>C</sub> =25°C Unless Otherwise Noted)			
V <sub>DSS</sub>	Drain-Source Voltage		60	V
V <sub>GSS</sub>	Gate-Source Voltage		±25	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
TJ	Maximum Junction Temperature		175	°C
T <sub>STG</sub>	Storage Temperature Range		-55 to 175	°C
Is	Diode Continuous Forward Current	T <sub>C</sub> =25°C	55	А
Mounted o	n Large Heat Sink	*		
I <sub>DM</sub>	Pulsed Drain Current *	T <sub>C</sub> =25°C	220**	А
1_	Continuous Drain Current		55	A
l <sub>D</sub>	Continuous Diain Current	T <sub>C</sub> =100°C	38	
D	T <sub>C</sub> =25°C	T <sub>C</sub> =25°C	100	_ w
P <sub>D</sub>	Maximum Power Dissipation $T_{C}=100^{\circ}C$		50	
$R_{ heta JC}$	Thermal Resistance-Junction to Case		1.5	°C/W
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient		110	°C/W
E <sub>AS</sub>	Drain-Source Avalanche Energy L=0.5mH		200***	mJ

Note : \* Repetitive rating ; pulse width limited by junction temperature 
\*\* Drain current is limited by junction temperature

# **Electrical Characteristics** $(T_c = 25^{\circ}C \text{ Unless Otherwise Noted})$

Symbol	Parameter	Test Conditions		HY1506		HY1506		Unit
Syllibol	rarameter rest conditions		Min.	Тур.	Max.	Onic		
Static Ch	aracteristics				,			
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250μA	60	65	-	V		
	Zero Gate Voltage Drain Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V	-	-	1	^		
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	T <sub>J</sub> =85°C	-	-	30	μА		
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{DS}=250\mu A$	1.0	1.6	3.0	V		
I <sub>GSS</sub>	Gate Leakage Current	$V_{GS}=\pm25V, V_{DS}=0V$	-	-	±100	nA		
D *	Drain Course On state Desistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =28A	-	10.5	13.5	mΩ		
R <sub>DS(ON)</sub> *	Orain-Source On-state Resistance V <sub>GS</sub> =4.5V, I <sub>DS</sub> =28A			13.5	15	mΩ		
Diode Ch	Diode Characteristics							
V <sub>SD</sub> *	Diode Forward Voltage	I <sub>SD</sub> =28A, V <sub>GS</sub> =0V	-	0.8	1.1	V		
t <sub>rr</sub>	Reverse Recovery Time	1 _20	_	50	-	ns		
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>DS</sub> =28A, dl <sub>SD</sub> /dt=100A/μι 	-	74	-	nC		

<sup>\*\*\*</sup> VD=48V



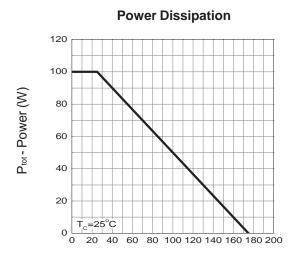
# **Electrical Characteristics (Cont.)** $(T_c = 25^{\circ}C \text{ Unless Otherwise Noted})$

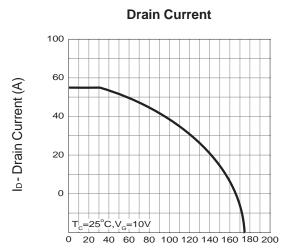
Symbol	Parameter Test Conditions -	Tost Conditions	Н	HY1506	i	Unit
Symbol		Min.	Тур.	Max.	Onit	
Dynamic	Characteristics					
$R_{G}$	Gate Resistance	V <sub>GS</sub> =0V,V <sub>DS</sub> =0V,F=1MHz	ı	1.2	ı	Ω
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V,	-	3522	1	
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =25V,	1	666	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	Frequency=1.0MHz	-	172	-	
t <sub>d(ON)</sub>	Turn-on Delay Time	$V_{DD}$ =30V, $R_{G}$ =4 $\Omega$ , $I_{DS}$ =28A, $V_{GS}$ =10V,	1	21	39	
T <sub>r</sub>	Turn-on Rise Time		-	25	48	ns
t <sub>d(OFF)</sub>	Turn-off Delay Time		ı	27	52	113
$T_f$	Turn-off Fall Time		1	31	58	
Gate Charge Characteristics						
Qg	Total Gate Charge	V <sub>DS</sub> =48V, V <sub>GS</sub> =10V, I <sub>DS</sub> =28A	-	62	-	
Q <sub>gs</sub>	Gate-Source Charge		-	6	-	nC
$Q_{gd}$	Gate-Drain Charge	103 =4: 1	-	11	-	

Note \* : Pulse test ; pulse width  $\leq$ 300 µs, duty cycle  $\leq$ 2%.



# **Typical Operating Characteristics**

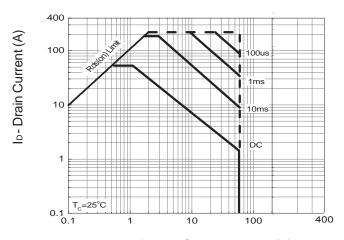




T<sub>c</sub>- Case Temperature (°C)

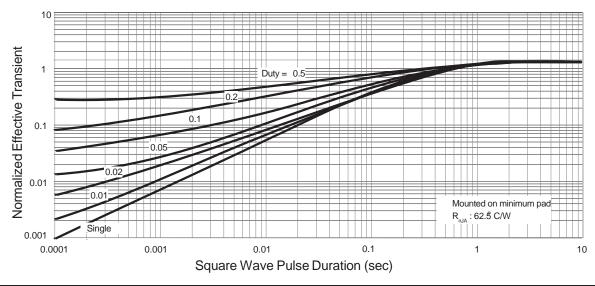
T<sub>c</sub>-Case Temperature (°C)

#### **Safe Operation Area**



V<sub>DS</sub> - Drain - Source Voltage (V)

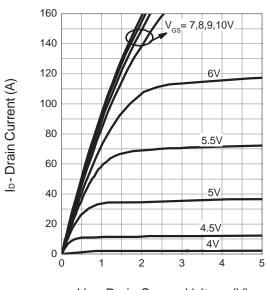
#### **Thermal Transient Impedance**



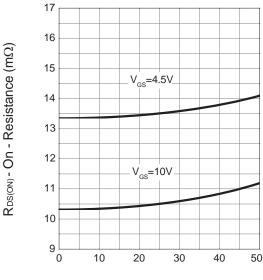


# **Typical Operating Characteristics (Cont.)**

#### **Output Characteristics**

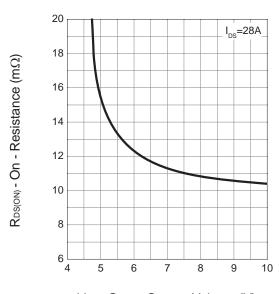


V<sub>DS</sub> - Drain-Source Voltage (V)



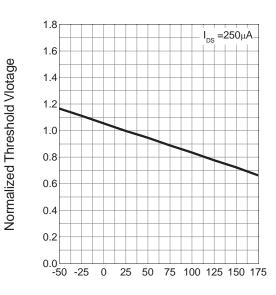
ID - Drain Current (A)

### **Drain-Source On Resistance**



V<sub>GS</sub> - Gate - Source Voltage (V)

#### **Gate Threshold Voltage**

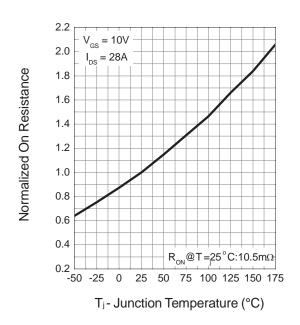


T<sub>j</sub> - Junction Temperature (°C)

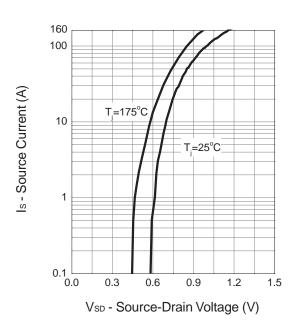


# **Typical Operating Characteristics (Cont.)**

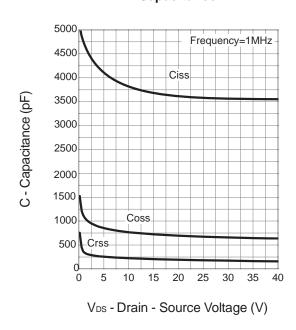
#### **Drain-Source On Resistance**



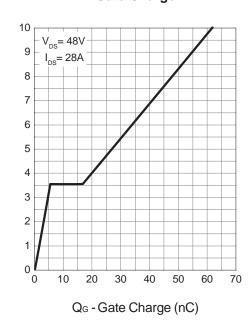
#### Source-Drain Diode Forward



#### Capacitance



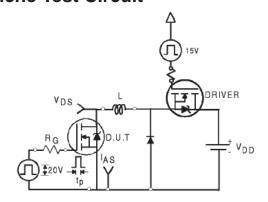
#### **Gate Charge**

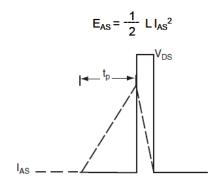


Ves - Gate-source Voltage (V)

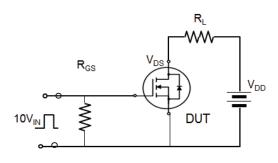


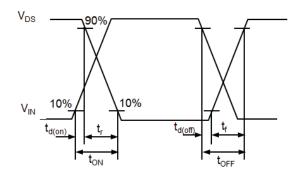
## **Avalanche Test Circuit**



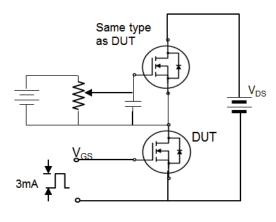


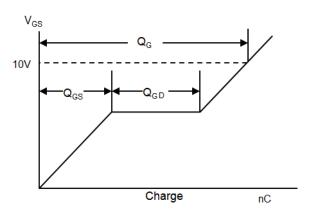
# **Switching Time Test Circuit**





# **Gate Charge Test Circuit**





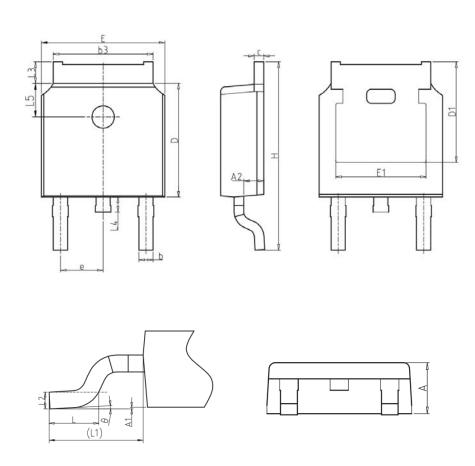


# **Device Per Unit**

Package Type	Unit	Quantity
TO-252-2L	Tube	75
TO-252-2L	Reel	2500
TO-251-3L	Tube	75
TO-251-3S	Tube	75

# **Package Information**

TO-252-2L

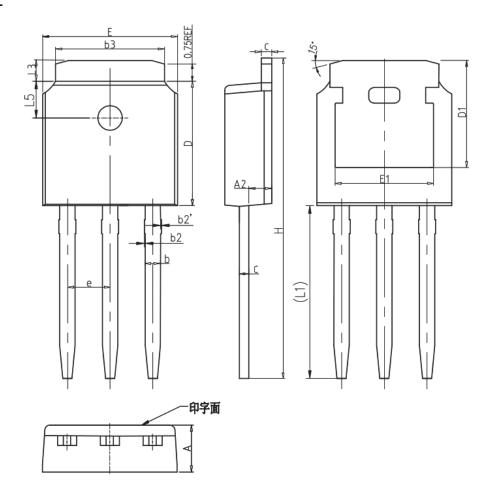


#### **COMMON DIMENSIONS**

SYMBOL		mm	
STIVIBUL	MIN	NOM	MAX
А	2.20	2.30	2.40
A1	0.00	-	0.20
A2	0.97	1.07	1.17
b	0.68	0.78	0.90
b3	5.20	5.33	5.50
С	0.43	0.53	0.63
D	5.98	6.10	6.22
D1	5.30REF		
Е	6.40	6.60	6.80
E1	4.63	-	ı
е		2.286BS0	
Н	9.40	10.10	10.50
L	1.38	1.50	1.75
L1		2.90REF	-
L2	0.51BSC		
L3	0.88	-	1.28
L4	-	-	1.00
L5	1.65	1.80	1.95
θ	0°	-	8°



### TO-251-3L

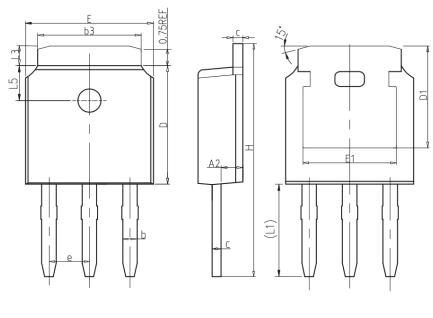


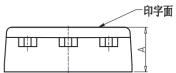
### COMMON DIMENSIONS

SYMBOL		mm	
STIVIBOL	MIN	NOM	MAX
А	2.20	2.30	2.40
A2	0.97	1.07	1.17
b	0.68	0.78	0.90
b2	0.00	0.04	0.10
b2'	0.00	0.04	0.10
b3	5.20	5.33	5.50
С	0.43	0.53	0.63
D	5.98	6.10	6.22
D1		5.30REF	
E	6.40	6.60	6.80
E1	4.63	-	-
е		2.286BSC	
Н	16.22	16.52	16.82
L1	9.15	9.40	9.65
L3	0.88	1.02	1.28
L5	1.65	1.80	1.95



### TO-251-3S



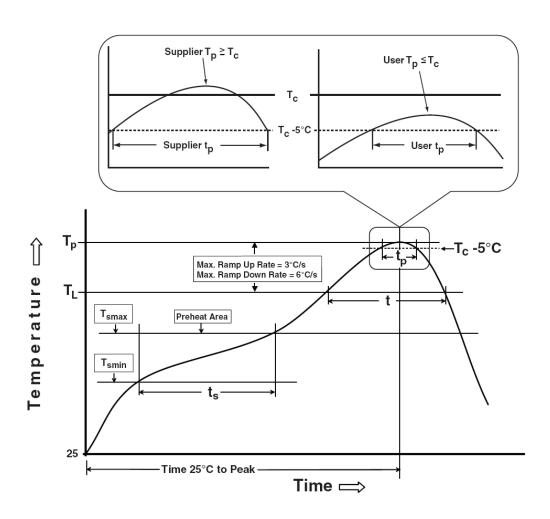


#### **COMMON DIMENSIONS**

CVMDOL		mm	
SYMBOL	MIN	NOM	MAX
А	2.20	2.30	2.40
A2	0.97	1.07	1.17
b	0.68	0.78	0.90
b3	5.20	5.33	5.50
С	0.43	0.53	0.63
D	5.98	6.10	6.22
D1		5.30REF	
E	6.40	6.60	6.80
E1	4.63	-	-
е		2.286BSC	
Н	10.00	11.22	11.44
L1	3.90	4.10	4.30
L3	0.88	1.02	1.28
L5	1.65	1.80	1.95



### **Classification Profile**



### **Classification Reflow Profiles**

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak Temperature min (T <sub>smin</sub> ) Temperature max (T <sub>smax</sub> ) Time (T <sub>smin</sub> to T <sub>smax</sub> ) (t <sub>s</sub> )	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds
Average ramp-up rate (T <sub>smax</sub> to T <sub>P</sub> )	3 °C/second max.	3°C/second max.
Liquidous temperature (T <sub>L</sub> ) Time at liquidous (t <sub>L</sub> )	183 °C 60-150 seconds	217 °C 60-150 seconds
Peak package body Temperature (T <sub>p</sub> )*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t <sub>P</sub> )** within 5°C of the specified classification temperature (T <sub>c</sub> )	20** seconds	30** seconds
Average ramp-down rate (T <sub>p</sub> to T <sub>smax</sub> )	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.

<sup>\*</sup> Tolerance for peak profile Temperature  $(T_p)$  is defined as a supplier minimum and a user maximum. \*\* Tolerance for time at peak profile temperature  $(t_p)$  is defined as a supplier minimum and a user maximum.

## HY1506D/U/S



Table 1. SnPb Eutectic Process – Classification Temperatures (Tc)

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures (Tc)

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm <sup>3</sup> 350-2000	Volume mm <sup>3</sup> >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

## **Reliability Test Program**

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	168Hrs/500Hrs/1000Hrs,Bias@125°C
PCT	JESD-22, A102	96 Hrs, 100% RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C

#### **Customer Service**

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